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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s): TANAKA et al

Serial No.: 09/942,213

Filed: August 30, 2001

For: Method And Apparatus For Inspecting A Semiconductor Device

Group: 2812

Examiner:

**PRELIMINARY AMENDMENT**

Assistant Commissioner for Patents  
Washington, D.C. 20231

December 27, 2001

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

**IN THE SPECIFICATION:**

Please replace the original specification with the attached Substitute Specification.

**IN THE ABSTRACT OF THE DISCLOSURE:**

Please replace the original abstract with the attached abstract.

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DEC 31 2001  
TC 2800 MAIL ROOM

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JUL 17 2002  
TECHNOLOGY CENTER 2800